



**An Assessment of the
United States Measurement System:
Addressing Measurement Barriers to
Accelerate Innovation**

Appendix D

**Contributors to the 2006 Assessment of
the USMS by NIST**

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We acknowledge that in preparing a list of contributors of this magnitude, there is always a possibility that someone may have been inadvertently missed and for this we apologize. We deeply appreciate all contributions to this effort.

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